



Dr. Markus Mezger

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“Soft Matter in Confinement: High-Energy and Resonant Soft X-Ray Reflectivity Studies”

Interfacial phenomena in physical, chemical, and biological systems are at the core of many of today's technological applications. High-energy and resonant soft x-ray reflectivity are complementary techniques that can provide information on buried structures, scarcely accessible by most conventional experimental methods. Our experiments include studies on the interface of ionic liquids with sapphire. From high energy x-ray reflectivity data we extracted an oscillatory profile comprised of alternating anion and cation enriched layers. In another example, I will discuss the side-chain orientation in liquid crystalline polymer thin films. Linear dichroism in soft x-ray reflectivity measurements on samples, covered by an amorphous polymer film, demonstrates the sensitivity to molecular orientation within buried layers.

Dienstag, 12. Januar 2010, 14.00 c.t.

Gebäude E2 6, Seminarraum E.04

Alle Interessenten sind herzlich eingeladen.

Die Sprecher des Graduiertenkollegs
Manfred Lücke und Ludger Santen

**Strukturbildung und Transport
in komplexen Systemen**